Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/620,862	ANVIN ET AL.	
Examiner	Art Unit	
Benjamin P. Geib	2181	

Benjamin P. Geib

	SEAR	CHED	
Class	Subclass	Date	Examiner
712	244	8/20/2007	BPG
712	235	8/20/2007	BPG
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INT	ERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NO (INCLUDING SEARCH) ·
	DATE	EXMR
Updated EAST search	8/20/2007	BPG
NPL search (Google Scholar and IEEE Xplore)	8/20/2007	BPG
Inventor name search	8/20/2007	BPG
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